

EBSD Workshop

3 – 4 November 2008

Dobřany, Czech Republic

You are invited to attend a two days EBSD workshop to be held at:

COMTES FHT a.s., 334 41 Dobřany, Czech Republic

03 November 2008

Registration from 1.30 – 2 p.m.

Lectures:

- The latest developments in SEM and FE-SEM technology (JEOL)
- Sample preparation using the JEOL Cross Sectional Polisher (JEOL)
- Introduction to Electron Backscatter Diffraction (Keith Dicks, Oxford Instruments)
- EBSD Applications (NN)

Participants are invited to join us for company dinner

04 November 2008, 09.30 a.m. – 4 p.m.

Live demonstrations & hands-on experience

- EBSD - How does it work?
- What am I using the technique for?
- How can I get the most out of my system?
- Why is sample preparation so important?

To register to attend, or find out more information, please contact:

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